

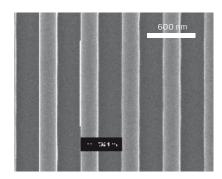
Large Area Nanogratings

1D, rectangular and hexagonal



Description

AMO offers gratings fabricated by inhouse interference lithography (IL). The IL technology allows producing large, coherent and periodic gratings with nearly constant pitch. Pattern transfer and further processing can be carried out according to customer requirements. Substrates up to 6 inch and any rectangular within.



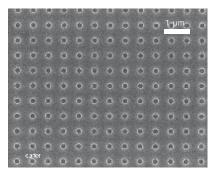
Linear Grating

Applications

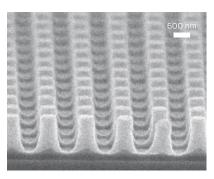
- ► Master for Imprint Templates
- ► Microoptics
- ► NanoBio Technology
- ▶ Sensor technology



All grating dimensions are specified and controlled during and after processing. Line width maps, LER characterisation and defect inspection are available on request.



Holes Pattern



Pillars Pattern



Specification

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Substrate material Silicon or fused silica Substrate thickness typical 500 µm to 650 µm Substrate size up to 6 inch and any rectangular within Grating pitch 300 nm to 2.500 nm Etch depth 90 nm to 2.500 nm Line width 40 nm to 2.500 nm Acting grating area up to 400 mm in diameter

Some specifications are matter of negotiation. For further details please contact us.





Nanophotonics

Masters and Stamps for Nanoimprint Lithography

AMO offers masters fabricated using various micro- and nanolithography techniques in combination with anisotropic etching.



Large Area Periodic Nanostructures

Our interference-lithography (IL) technology allows producing large, spatial coherent and periodic gratings with constant pitch. Pattern transfer and further processing can be carried out according to customer requirements to achieve high aspect ratio gratings with vertical sidewalls.

| Pattern type | 1D, rectangular, hexagonal | |
|---------------------|--------------------------------------|--|
| Substrate material | Silicon or fused silica | |
| Substrate thickness | typical 500 μm to 650 μm | |
| Substrate size | 2, 4, 6 and 8 inch | |
| Grating pitch | 180 nm to 2500 nm | |
| Etch depth | up to 2500 nm | |
| Line width | 40 nm to 1500 nm | |
| Active grating | area up to 90% of the substrate size | |
| | | |

Some specifications are matter of negotiation. For further details please contact us.



All grating dimensions are specified and controlled during and after processing. Line-width maps, line-edge roughness characterisation and defect inspection are available on request.



Using our e-beam lithography (EBL), we can realize arbitrary nanoscale patterns. Our system provides resolution down to a few ten nanometers. The definition of large active-areas is limited by the writing time, which is pattern dependent. Pattern transfer into silicon or other material is possible. Quotes can be provided ased on an electronic design, preferable in GDS format.



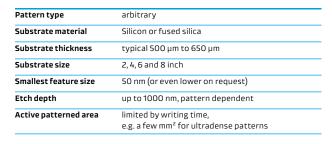
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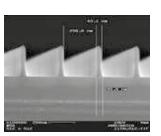
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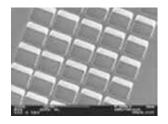
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Arbitrary Microstructures

Masters can easily be produced using photolithography. Here micrometer features can be defined and etched up to 10 µm into the substrate. This technique requires a photomask that can be designed to satisfy the customer's needs or chosen among our masks on stock.



Mask Aligner

| Pattern type | arbitrary |
|-----------------------|----------------------------------|
| Substrate material | Silicon or fused silica |
| Substrate thickness | typical 500 μm to 650 μm |
| Substrate size | up to 8 inch and any size within |
| Smallest feature size | 2 μm |
| Etch depth | up to 10 μm |
| Active patterned area | full substrate |

i-line Stepper

| Pattern type | Arbitrary field size up to 20x20 mm² |
|-----------------------|--------------------------------------|
| Substrate material | Silicon or fused silica |
| Substrate thickness | typical 500 μm to 650 μm |
| Substrate size | 6 inch only |
| Smallest feature size | 0,5 µm |
| Etch depth | up to 5 μm |
| Active patterned area | full substrate |

Advanced masters using mixed technology

E-beam and photolithography can be combined on request to realize particularly complex masters.

- ▶ Mix-Match between i-line and EBL lithography
- ▶ Multi-level-masters, for 3D applications

